
Record 1 of 56**Author(s):** Stallinga, P**Title:** Electronic transport in organic materials: comparison of band theory with percolation/(variable range) hopping theory.**Source:** Advanced materials (Deerfield Beach, Fla.)**Volume:** 23**Issue:** 30**Pages:** 3356-62**DOI:** 10.1002/adma.201101129**Published:** 2011-Aug-9**Total Times Cited:** 0**ISSN:** 1521-4095

Record 2 of 56**Author(s):** Silva, H.; Gomes, H. L.; Pogorelov, Yu. G.; Stallinga, P.; de Leeuw, D. M.; Araujo, J. P.; Sousa, J. B.; Meskers, S. C. J.; Kakazei, G.; Cardoso, S.; Freitas, P. P.**Title:** Resistive switching in nanostructured thin films**Source:** APPLIED PHYSICS LETTERS**Volume:** 94**Issue:** 20**Article Number:** 202107**DOI:** 10.1063/1.3134484**Published:** MAY 18 2009**Times Cited in Web of Science:** 4**Total Times Cited:** 4**ISSN:** 0003-6951

Record 3 of 56**Author(s):** Encarnacao, Joao M.; Baltazar, Raul; Stallinga, Peter; Ferreira, Guilherme N. M.**Title:** Piezoelectric biosensors assisted with electroacoustic impedance spectroscopy: a tool for accurate quantitative molecular recognition analysis**Source:** JOURNAL OF MOLECULAR RECOGNITION**Volume:** 22**Issue:** 2**Pages:** 129-137**DOI:** 10.1002/jmr.907**Published:** MAR-APR 2009**Conference Title:** 17th Biennial Meeting of the International-Society-for-Molecular-Recognition**Conference Date:** JUL 08-12, 2007**Conference Location:** New York, NY**Sponsor(s):** Int Soc Mole Recognit**Times Cited in Web of Science:** 1**Total Times Cited:** 1**ISSN:** 0952-3499

Record 4 of 56

Author(s): Stallinga, P.; Benvenho, A. R. V.; Smits, E. C. P.; Mathijssen, S. G. J.; Colle, M.; Gomes, H. L.; de Leeuw, D. M.

Title: Determining carrier mobility with a metal-insulator-semiconductor structure

Source: ORGANIC ELECTRONICS

Volume: 9

Issue: 5

Pages: 735-739

DOI: 10.1016/j.orgel.2008.05.007

Published: OCT 2008

Times Cited in Web of Science: 2

Total Times Cited: 2

ISSN: 1566-1199

Record 5 of 56

Author(s): Stallinga, P.; Gomes, H. L.

Title: Modeling electrical characteristics of thin-film field-effect transistors III. Normally-on devices

Source: SYNTHETIC METALS

Volume: 158

Issue: 11

Pages: 473-478

DOI: 10.1016/j.synthmet.2008.03.011

Published: JUL 2008

Times Cited in Web of Science: 0

Total Times Cited: 0

ISSN: 0379-6779

Record 6 of 56

Author(s): Stallinga, Peter; Roy, V. A. L.; Xu, Zong-Xiang; Xiang, Hai-Feng; Che, Chi-Ming

Title: Metal-insulator-metal transistors

Source: ADVANCED MATERIALS

Volume: 20

Issue: 11

Pages: 2120-+

DOI: 10.1002/adma.200702525

Published: JUN 4 2008

Times Cited in Web of Science: 1

Total Times Cited: 1

ISSN: 0935-9648

Record 7 of 56

Author(s): Casteleiro, C.; Schwarz, R.; Mardolcar, U.; Macarico, A.; Martins, J.; Vieira, M.; Wuensch, F.; Kunst, M.; Morgado, E.; Stallinga, P.; Gomes, H. L.

Title: Spatially-resolved photocapacitance measurements to study defects in a-Si : H based p-i-n particle detectors

Source: THIN SOLID FILMS

Volume: 516

Issue: 15

Pages: 5118-5121

DOI: 10.1016/j.tsf.2008.01.012

Published: JUN 2 2008

Times Cited in Web of Science: 0

Total Times Cited: 0

ISSN: 0040-6090

Record 8 of 56

Author(s): Casteleiro, C.; Gomes, H. L.; Stallinga, P.; Bentes, L.; Ayouchi, R.; Schwarz, R.

Title: Study of trap states in zinc oxide (ZnO) thin films for electronic applications

Source: JOURNAL OF NON-CRYSTALLINE SOLIDS

Volume: 354

Issue: 19-25

Pages: 2519-2522

DOI: 10.1016/j.jnoncrysol.2007.10.059

Published: MAY 1 2008

Conference Title: 22nd International Conference on Amorphous and Nanocrystalline Semiconductors

Conference Date: AUG 19-24, 2007

Conference Location: Breckenridge, CO

Sponsor(s): Univ Toledo, PVIC; NREL; United Solar; Forschungszentrum Julich; Hewlett Packard; OptiSolar; PARC; Sanyo; Sharp

Times Cited in Web of Science: 4

Total Times Cited: 5

ISSN: 0022-3093

Record 9 of 56

Author(s): Schwarz, R.; Mardolcar, U.; Vygranenko, Y.; Vieira, M.; Casteleiro, C.; Stallinga, P.; Gomes, H.

Title: Photocapacitance measurements in irradiated a-Si : H based detectors

Source: JOURNAL OF NON-CRYSTALLINE SOLIDS

Volume: 354

Issue: 19-25

Pages: 2176-2180

DOI: 10.1016/j.jnoncrysol.2007.09.049

Published: MAY 1 2008

Conference Title: 22nd International Conference on Amorphous and Nanocrystalline Semiconductors

Conference Date: AUG 19-24, 2007

Conference Location: Breckenridge, CO

Sponsor(s): Univ Toledo, PVIC; NREL; United Solar; Forschungszentrum Julich; Hewlett Packard; OptiSolar; PARC; Sanyo; Sharp

Times Cited in Web of Science: 0

Total Times Cited: 0

ISSN: 0022-3093

Record 10 of 56

Author(s): Gomes, H. L.; Benvenho, A. R. V.; de Leeuw, D. M.; Colle, M.; Stallinga, P.; Verbakel, F.; Taylor, D. M.

Title: Switching in polymeric resistance random-access memories (RRAMS)

Source: ORGANIC ELECTRONICS

Volume: 9

Issue: 1

Pages: 119-128

DOI: 10.1016/j.orgel.2007.10.002

Published: FEB 2008

Times Cited in Web of Science: 15

Total Times Cited: 15

ISSN: 1566-1199

Record 11 of 56

Author(s): Timmerman, D.; Izeddin, I.; Stallinga, P.; Yassievich, I. N.; Gregorkiewicz, T.

Title: Space-separated quantum cutting with silicon nanocrystals for photovoltaic applications

Source: NATURE PHOTONICS

Volume: 2

Issue: 2

Pages: 105-109

DOI: 10.1038/nphoton.2007.279

Published: FEB 2008

Times Cited in Web of Science: 54

Total Times Cited: 55

ISSN: 1749-4885

Record 12 of 56

Author(s): Stallinga, P.; Gomes, H. L.

Title: Metal contacts in thin-film transistors

Source: ORGANIC ELECTRONICS

Volume: 8

Issue: 4

Pages: 300-304

DOI: 10.1016/j.orgel.2006.11.004

Published: AUG 2007

Times Cited in Web of Science: 3

Total Times Cited: 4

ISSN: 1566-1199

Record 13 of 56

Author(s): Xu, Zong-Xiang; Roy, V. A. L.; Stallinga, Peter; Muccini, Michele; Toffanin, Stefano; Xiang, Hei-Feng; Che, Chi-Ming

Title: Nanocomposite field effect transistors based on zinc oxide/polymer blends

Source: APPLIED PHYSICS LETTERS

Volume: 90

Issue: 22

Article Number: 223509

DOI: 10.1063/1.2740478

Published: MAY 28 2007

Times Cited in Web of Science: 22

Total Times Cited: 23

ISSN: 0003-6951

Record 14 of 56

Author(s): Encarnacao, Joao M.; Stallinga, Peter; Ferreira, Guilherme N. M.

Title: Influence of electrolytes in the QCM response: Discrimination and quantification of the interference to correct microgravimetric data

Source: BIOSENSORS & BIOELECTRONICS

Volume: 22

Issue: 7

Pages: 1351-1358

DOI: 10.1016/j.bios.2006.06.011

Published: FEB 15 2007

Times Cited in Web of Science: 5

Total Times Cited: 5

ISSN: 0956-5663

Record 15 of 56

Author(s): Roy, Vellaisamy A. L.; Xu, Zong-Xiang; Stallinga, Peter; Xiang, Hai-Feng; Yan, Beiping; Che, Chi-Ming

Editor(s): Arimoto, H

Title: Nanocomposite field effect transistors based on Zinc oxide/polymer blends

Source: MICROPROCESSES AND NANOTECHNOLOGY 2007, DIGEST OF PAPERS

Pages: 104-105

Published: 2007

Conference Title: 20th International Microprocesses and Nanotechnology Conference

Conference Date: NOV 05-08, 2007

Conference Location: Kyoto, JAPAN

Sponsor(s): Japan Soc Appl Phys; IEEE Elect Devices Soc; Assoc Super-Adv Elect Technol; Inst Elect, Informat & Commun Engineers Japan; Japan Soc Precis Engn; Japanese Soc Synchrotron Radiat Res; Japanese Soc Microscopy; Surface Sci Soc Japan; Vacuum Soc Japan

Times Cited in Web of Science: 0

Total Times Cited: 0

ISBN: 978-4-9902472-4-9

Record 16 of 56

Author(s): Stallinga, P.; Gomes, H. L.

Title: Thin-film field-effect transistors: The effects of traps on the bias and temperature dependence of field-effect mobility, including the Meyer-Neldel rule

Source: ORGANIC ELECTRONICS

Volume: 7

Issue: 6

Pages: 592-599

DOI: 10.1016/j.orgel.2006.10.003

Published: DEC 2006

Times Cited in Web of Science: 4

Total Times Cited: 4

ISSN: 1566-1199

Record 17 of 56

Author(s): Stallinga, P.; Gomes, H. L.

Title: Modeling electrical characteristics of thin-film field-effect transistors I. Trap-free materials

Source: SYNTHETIC METALS

Volume: 156

Issue: 21-24

Pages: 1305-1315
DOI: 10.1016/j.synthmet.2006.09.015
Published: DEC 1 2006
Times Cited in Web of Science: 10
Total Times Cited: 10
ISSN: 0379-6779

Record 18 of 56

Author(s): Stallinga, P.; Gomes, H. L.
Title: Modeling electrical characteristics of thin-film field-effect transistors II: Effects of traps and impurities
Source: SYNTHETIC METALS
Volume: 156
Issue: 21-24
Pages: 1316-1326
DOI: 10.1016/j.synthmet.2006.09.008
Published: DEC 1 2006
Times Cited in Web of Science: 9
Total Times Cited: 9
ISSN: 0379-6779

Record 19 of 56

Author(s): Gomes, H. L.; Stallinga, P.; Colle, M.; Biscarini, F.; de Leeuw, D. M.
Title: The effect of water related traps on the reliability of organic based transistors
Source: JOURNAL OF NON-CRYSTALLINE SOLIDS
Volume: 352
Issue: 9-20
Pages: 1761-1764
DOI: 10.1016/j.jnoncrysol.2005.10.069
Published: JUN 15 2006
Conference Title: 21st International Conference on Amorphous and Nanocrystalline Semiconductors
Conference Date: SEP 04-09, 2005
Conference Location: Lisbon, PORTUGAL
Times Cited in Web of Science: 10
Total Times Cited: 10
ISSN: 0022-3093

Record 20 of 56

Author(s): Gomes, HL; Stallinga, P; Colle, M; de Leeuw, DM; Biscarini, F
Title: Electrical instabilities in organic semiconductors caused by trapped supercooled water
Source: APPLIED PHYSICS LETTERS
Volume: 88
Issue: 8
Article Number: 082101
DOI: 10.1063/1.2178410
Published: FEB 20 2006
Times Cited in Web of Science: 34
Total Times Cited: 33
ISSN: 0003-6951

Record 21 of 56**Author(s):** Gomes, HL; Stallinga, P; de Leeuw, DM**Editor(s):** Vilarinho, PM**Title:** Organic materials for active layers in transistors: Study of the electrical stability properties**Source:** ADVANCED MATERIALS FORUM III, PTS 1 AND 2**Book Series Title:** MATERIALS SCIENCE FORUM**Volume:** 514-516**Pages:** 33-37**Part:** Part 1-2**Published:** 2006**Conference Title:** 3rd International Materials Symposium/12th Meeting of the Sociedade-Portuguesa-da-Materials (Materials 2005/SPM)**Conference Date:** MAR 20-23, 2005**Conference Location:** Univ Aveiro, Aveiro, PORTUGAL**Sponsor(s):** Portuguese Mat Soc; Mat Network Atlantic Arc; CiCECO; BPI; Bayer Mat Sci; DURIT; IZASA; GIC; Novagres; Rauschert; CRIOLAB CRYOGENICS Vacuum Syst Vacuum Chambers; FCT; NTI EUROPE; Fdn Calouste Gulbenkian; ScienTec; ThermoLab; Papelave; cienciapt net; Air Liquide**Conference Host:** Univ Aveiro**Times Cited in Web of Science:** 0**Total Times Cited:** 0**ISSN:** 0255-5476**ISBN:** *****

Record 22 of 56**Author(s):** Stallinga, Peter; Gomes, Henrique L.**Title:** Light-emitting thin-film field-effect transistors**Source:** OPTICA APPLICATA**Volume:** 36**Issue:** 2-3**Pages:** 373-380**Published:** 2006**Times Cited in Web of Science:** 0**Total Times Cited:** 0**ISSN:** 0078-5466

Record 23 of 56**Author(s):** Stallinga, P; Gomes, HL**Title:** Trap states as an explanation for the Meyer-Neldel rule in semiconductors**Source:** ORGANIC ELECTRONICS**Volume:** 6**Issue:** 3**Pages:** 137-141**DOI:** 10.1016/j.orgel.2005.03.008**Published:** JUN 2005**Times Cited in Web of Science:** 9**Total Times Cited:** 9**ISSN:** 1566-1199

Record 24 of 56

Author(s): Gomes, HL; Stallinga, P; Dinelli, F; Murgia, M; Biscarini, F; de Leeuw, DM; Muccini, M; Mullen, K

Title: Electrical characterization of organic based transistors: stability issues

Source: POLYMERS FOR ADVANCED TECHNOLOGIES

Volume: 16

Issue: 2-3

Special Issue: SI

Pages: 227-231

DOI: 10.1002/pat.558

Published: FEB-MAR 2005

Conference Title: 7th International Symposium on Polymers for Advanced Technologies

Conference Date: SEP 21-24, 2003

Conference Location: Ft Lauderdale, FL

Times Cited in Web of Science: 25

Total Times Cited: 26

ISSN: 1042-7147

Record 25 of 56

Author(s): Santato, C; Capelli, R; Loi, MA; Murgia, M; Cicoira, F; Roy, VAL; Stallinga, P; Zamboni, R; Rost, C; Karg, SE; Muccini, M

Title: Tetracene-based organic light-emitting transistors: optoelectronic properties and electron injection mechanism

Source: SYNTHETIC METALS

Volume: 146

Issue: 3

Pages: 329-334

DOI: 10.1016/j.synthmet.2004.08.028

Published: NOV 3 2004

Conference Title: Symposium on Organic Field-Effect Transistors - Towards Molecular Scale held at the 2004 Annual E-MRS Spring Meeting

Conference Date: MAY 24-28, 2004

Conference Location: Strasbourg, FRANCE

Sponsor(s): European Mat Res Soc

Times Cited in Web of Science: 55

Total Times Cited: 56

ISSN: 0379-6779

Record 26 of 56

Author(s): Stallinga, P; Gomes, HL; Biscarini, F; Murgia, M; de Leeuw, DM

Title: Electronic transport in field-effect transistors of sexithiophene

Source: JOURNAL OF APPLIED PHYSICS

Volume: 96

Issue: 9

Pages: 5277-5283

DOI: 10.1063/1.1789279

Published: NOV 1 2004

Times Cited in Web of Science: 39

Total Times Cited: 40

ISSN: 0021-8979

Record 27 of 56

Author(s): Gomes, HL; Stallinga, P; Dinelli, F; Murgia, M; Biscarini, F; de Leeuw, DM; Muck, T; Geurts, J; Molenkamp, LW; Wagner, V

Title: Bias-induced threshold voltages shifts in thin-film organic transistors

Source: APPLIED PHYSICS LETTERS

Volume: 84

Issue: 16

Pages: 3184-3186

DOI: 10.1063/1.1713035

Published: APR 19 2004

Times Cited in Web of Science: 93

Total Times Cited: 93

ISSN: 0003-6951

Record 28 of 56

Author(s): Gomes, HL; Leite, RB; Afonso, R; Stallinga, P; Cancela, ML

Editor(s): Rocha, D; Sarro, PM; Vellekoop, MJ

Title: A microelectrode impedance method to measure interaction of cells

Source: PROCEEDINGS OF THE IEEE SENSORS 2004, VOLS 1-3

Book Series Title: IEEE Sensors

Pages: 1011-1013

DOI: 10.1109/ICSENS.2004.1426344

Published: 2004

Conference Title: IEEE Sensors 2004 Conference

Conference Date: OCT 24-27, 2004

Conference Location: Vienna Univ Technol, Vienna, AUSTRIA

Sponsor(s): IEEE

Conference Host: Vienna Univ Technol

Times Cited in Web of Science: 0

Total Times Cited: 0

ISSN: 1930-0395

ISBN: 0-7803-8692-2

Record 29 of 56

Author(s): Bentes, E; Gomes, HL; Stallinga, P; Moura, L

Editor(s): Rocha, D; Sarro, PM; Vellekoop, MJ

Title: Detection of explosive vapors using organic thin-film transistors

Source: PROCEEDINGS OF THE IEEE SENSORS 2004, VOLS 1-3

Book Series Title: IEEE Sensors

Pages: 766-769

DOI: 10.1109/ICSENS.2004.1426281

Published: 2004

Conference Title: IEEE Sensors 2004 Conference

Conference Date: OCT 24-27, 2004

Conference Location: Vienna Univ Technol, Vienna, AUSTRIA

Sponsor(s): IEEE

Conference Host: Vienna Univ Technol

Times Cited in Web of Science: 1

Total Times Cited: 1

ISSN: 1930-0395

ISBN: 0-7803-8692-2

Record 30 of 56

Author(s): Johannesen, P; Jakobsen, R; Stallinga, P; Nielsen, BB; Byberg, JR

Title: Silicon vacancy containing two hydrogen atoms studied with electron paramagnetic resonance and infrared absorption spectroscopy

Source: PHYSICAL REVIEW B

Volume: 66

Issue: 23

Article Number: 235201

DOI: 10.1103/PhysRevB.66.235201

Published: DEC 15 2002

Times Cited in Web of Science: 5

Total Times Cited: 5

ISSN: 1098-0121

Record 31 of 56

Author(s): Stallinga, P; Gomes, HL; Murgia, M; Mullen, K

Title: Interface state mapping in a Schottky barrier of the organic semiconductor terrylene

Source: ORGANIC ELECTRONICS

Volume: 3

Issue: 1

Pages: 43-51

Article Number: PII S1566-1199(02)00024-1

DOI: 10.1016/S1566-1199(02)00024-1

Published: MAR 2002

Times Cited in Web of Science: 23

Total Times Cited: 23

ISSN: 1566-1199

Record 32 of 56

Author(s): Stallinga, P; Gomes, HL; Charas, A; Morgado, J; Alcacer, L

Title: Electrical characterization of pn-junctions of PPV and silicon

Source: SYNTHETIC METALS

Volume: 121

Issue: 1-3

Special Issue: SI

Pages: 1535-1536

DOI: 10.1016/S0379-6779(00)01174-7

Published: MAR 15 2001

Conference Title: 16th International Conference on Science and Technology of Synthetic Metals (ICSM 2000)

Conference Date: JUL 15-21, 2000

Conference Location: GASTEIN, AUSTRIA

Times Cited in Web of Science: 1

Total Times Cited: 1

ISSN: 0379-6779

Record 33 of 56**Author(s):** Rodrigues, AM; Gomes, HL; Stallinga, P; Pereira, L; Pereira, E**Title:** Electrical characterization of CVD diamond-n(+) silicon junctions**Source:** DIAMOND AND RELATED MATERIALS**Volume:** 10**Issue:** 3-7**Special Issue:** SI**Pages:** 858-862**DOI:** 10.1016/S0925-9635(00)00571-9**Published:** MAR-JUL 2001**Conference Title:** 11th European Conference on Diamond, Diamond-like Materials, Carbon Nanotubes, Nitrides and Silicon Carbide (Diamond 2000)**Conference Date:** SEP 03-08, 2000**Conference Location:** OPORTO, PORTUGAL**Sponsor(s):** De Beers Ind Diamonds (UK) Ltd; GFD Gesell Diamantprod mbH; Philips Res Labs; Elsevier Sci**Times Cited in Web of Science:** 9**Total Times Cited:** 9**ISSN:** 0925-9635**Record 34 of 56****Author(s):** Stallinga, P; Gomes, HL; Rost, H; Holmes, AB; Harrison, MG; Friend, RH**Title:** Minority-carrier effects in poly-phenylenevinylene as studied by electrical characterization**Source:** JOURNAL OF APPLIED PHYSICS**Volume:** 89**Issue:** 3**Pages:** 1713-1724**DOI:** 10.1063/1.1334634**Published:** FEB 1 2001**Times Cited in Web of Science:** 11**Total Times Cited:** 11**ISSN:** 0021-8979**Record 35 of 56****Author(s):** Stallinga, P; Gomes, HL; Rost, H; Holmes, AB; Harrison, MG; Friend, RH**Title:** Electronic levels in MEH-PPV**Source:** SYNTHETIC METALS**Volume:** 111**Pages:** 535-537**DOI:** 10.1016/S0379-6779(99)00413-0**Published:** JUN 1 2000**Conference Title:** 2nd International Conference on Electroluminescence of Molecular Materials and Related Phenomena (ICEL-2)**Conference Date:** MAY 15-18, 1999**Conference Location:** SHEFFIELD, ENGLAND**Sponsor(s):** Univ Sheffield, Dept Phys & Astronomy, Electr & Photon Mol Mat Grp**Times Cited in Web of Science:** 16**Total Times Cited:** 16**ISSN:** 0379-6779

Record 36 of 56

Author(s): Stallinga, P; Gomes, HL; Rost, H; Holmes, AB; Harrison, MG; Friend, RH; Biscarini, F; Taliani, C; Jones, GW; Taylor, DM

Title: Determination of deep and shallow levels in conjugated polymers by electrical methods

Source: PHYSICA B-CONDENSED MATTER

Volume: 273-4

Pages: 923-926

DOI: 10.1016/S0921-4526(99)00555-4

Published: DEC 1999

Conference Title: 20th International Conference on Defects in Semiconductors (ICDS-20)

Conference Date: JUL 26-30, 1999

Conference Location: BERKELEY, CA

Sponsor(s): Air Force Off Sci Res; Amer Xtal Technol Inc; Appl Mat Inc; Bell Labs Lucent Technol; Hewlett Packard Lab; IBM; Intel Corp; Lawrence Berkeley Natl Lab; Off Naval Res; Sula Technol; Xeeox Palo Alto Res Ctr

Times Cited in Web of Science: 8

Total Times Cited: 8

ISSN: 0921-4526

Record 37 of 56

Author(s): Stallinga, P; Gomes, HL; Jones, GW; Taylor, DM

Title: Electrical study of impurity states in conjugated polymers

Source: SYNTHETIC METALS

Volume: 101

Issue: 1-3

Pages: 496-497

DOI: 10.1016/S0379-6779(98)01292-2

Published: MAY 1999

Conference Title: International Conference on Science and Technology of Synthetic Metals (ICSM 98)

Conference Date: JUL 12-18, 1998

Conference Location: MONTPELLIER, FRANCE

Times Cited in Web of Science: 3

Total Times Cited: 3

ISSN: 0379-6779

Record 38 of 56

Author(s): Gomes, HL; Stallinga, P; Rost, H; Holmes, AB; Harrison, MG; Friend, RH

Title: Analysis of deep levels in a phenylenevinylene polymer by transient capacitance methods

Source: APPLIED PHYSICS LETTERS

Volume: 74

Issue: 8

Pages: 1144-1146

DOI: 10.1063/1.123469

Published: FEB 22 1999

Times Cited in Web of Science: 38

Total Times Cited: 37

ISSN: 0003-6951

Record 39 of 56

Author(s): Stallinga, P; Gomes, HL; Jones, GW; Taylor, DM

Title: Electrical characterization of semiconducting polymers

Source: ACTA PHYSICA POLONICA A

Volume: 94

Issue: 3

Pages: 545-548

Published: SEP 1998

Conference Title: XXVII International School on Physics of Semiconducting Compounds

Conference Date: JUN 07-12, 1998

Conference Location: JASZOWIEC, POLAND

Sponsor(s): Polish Acad Sci, Inst Phys; Warsaw Univ, Fac Phys; Polish Acad Sci, High Pressure Res Ctr; Comm Sci Res; Minist Natl Educ; Fdn Pro Physica; Polish Physical Soc; UNESCO; Leopold Kronenberg Fdn; Uni-Export Instruments Ltd (Oxford Instruments representative)

Times Cited in Web of Science: 2

Total Times Cited: 2

ISSN: 0587-4246

Record 40 of 56

Author(s): Stallinga, P; Johannesen, P; Herstrom, S; Nielsen, KB; Nielsen, BB; Byberg, JR

Title: Electron paramagnetic resonance study of hydrogen-vacancy defects in crystalline silicon

Source: PHYSICAL REVIEW B

Volume: 58

Issue: 7

Pages: 3842-3852

DOI: 10.1103/PhysRevB.58.3842

Published: AUG 15 1998

Times Cited in Web of Science: 46

Total Times Cited: 46

ISSN: 0163-1829

Record 41 of 56

Author(s): Prasad, A; Stallinga, P; Liu, X; Weber, ER

Title: Origin of the magnetic circular dichroism of absorption of the arsenic antisite in GaAs and Al_xGa_{1-x}As

Source: PHYSICAL REVIEW B

Volume: 57

Issue: 8

Pages: R4214-R4217

DOI: 10.1103/PhysRevB.57.R4214

Published: FEB 15 1998

Times Cited in Web of Science: 2

Total Times Cited: 2

ISSN: 1098-0121

Record 42 of 56

Author(s): Stallinga, P; Nielsen, BB

Title: Comment on "Microscopic identification and electronic structure of a di-hydrogen-vacancy complex in silicon by optical detection of magnetic resonance"

Source: PHYSICAL REVIEW LETTERS

Volume: 80
Issue: 2
Pages: 422-422
DOI: 10.1103/PhysRevLett.80.422
Published: JAN 12 1998
Times Cited in Web of Science: 8
Total Times Cited: 8
ISSN: 0031-9007

Record 43 of 56

Author(s): Stallinga, P; Nielsen, BB
Title: Study of di-hydrogen-monovacancy defect in silicon
Source: ACTA PHYSICA POLONICA A
Volume: 92
Issue: 5
Pages: 989-992
Published: NOV 1997
Conference Title: XXVI International School on Physics of Semiconducting Compounds
Conference Date: JUN 06-13, 1997
Conference Location: JASZOWIEC, POLAND
Sponsor(s): Polish Acad Sci, Inst Phys; Warsaw Univ, Fac Phys; Polish Acad Sci, High Pressure Res Ctr; Polish State Comm Sci Res; Minist Natl Educ. Poland; Polish Acad Sci, Comm Phys; Polish Acad Sci, Off Int Relat; EC Program Tempus Tropous; Fdn Pro Phys; Polish Phys Soc; UNESCO; Oxford Instruments, Uni Export Instruments Ltd; Universal Elektron Import
Times Cited in Web of Science: 2
Total Times Cited: 2
ISSN: 0587-4246

Record 44 of 56

Author(s): Nielsen, BB; Johannesen, P; Stallinga, P; Nielsen, KB; Byberg, JR
Title: Identification of the silicon vacancy containing a single hydrogen atom by EPR
Source: PHYSICAL REVIEW LETTERS
Volume: 79
Issue: 8
Pages: 1507-1510
DOI: 10.1103/PhysRevLett.79.1507
Published: AUG 25 1997
Times Cited in Web of Science: 51
Total Times Cited: 51
ISSN: 0031-9007

Record 45 of 56

Author(s): Johannesen, P; Byberg, JR; Nielsen, BB; Stallinga, P; Nielsen, KB
Editor(s): Davies, G; Nazare, MH
Title: Identification of VH in silicon by EPR
Source: DEFECTS IN SEMICONDUCTORS - ICDS-19, PTS 1-3
Book Series Title: MATERIALS SCIENCE FORUM
Volume: 258-2

Pages: 515-520

Part: Part 1-3

Published: 1997

Conference Title: 19th International Conference on Defects in Semiconductors (ICDS-19)

Conference Date: JUL, 1997

Conference Location: AVEIRO, PORTUGAL

Sponsor(s): European Union DG XII Sci Res & Dev; Fundacao Calouste Gulbenkian; Junta Nacl Investigacio Cient & Tecnol; USA Res Off; Trans Tech Publicat Ltd; USN Off Naval Res Grant

Times Cited in Web of Science: 6

Total Times Cited: 6

ISSN: 0255-5476

ISBN: 0-87849-786-2

Record 46 of 56

Author(s): STALLINGA, P; WALUKIEWICZ, W; WEBER, ER; BECLA, P; LAGOWSKI, J

Title: ELECTRON-PARAMAGNETIC-RESONANCE STUDY OF SE-DOPED ALSB - EVIDENCE FOR NEGATIVE-U OF THE DX CENTER

Source: ACTA PHYSICA POLONICA A

Volume: 88

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Pages: 1043-1047

Published: NOV 1995

Conference Title: XXIV International School on Physics of Semiconducting Compounds

Conference Date: MAY 27-JUN 02, 1995

Conference Location: JASZOWIEC, POLAND

Sponsor(s): Polish Acad Sci Warsaw, Inst Phys; Warsaw Univ, Fac Phys; Polish Acad Sci Warsaw, High Pressure Res Ctr

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Total Times Cited: 1

ISSN: 0587-4246

Record 47 of 56

Author(s): STALLINGA, P; WALUKIEWICZ, W; WEBER, ER; BECLA, P; LAGOWSKI, J

Title: ELECTRON-PARAMAGNETIC-RESONANCE STUDY OF SE-DOPED ALSB - EVIDENCE FOR NEGATIVE-U OF THE DX-CENTER

Source: PHYSICAL REVIEW B

Volume: 52

Issue: 12

Pages: R8609-R8612

Published: SEP 15 1995

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ISSN: 0163-1829

Record 48 of 56

Author(s): PRASAD, A; LIU, X; STALLINGA, P; WEBER, ER; VERMA, AK; SMITH, JS

Editor(s): Ashok, S; Chevallier, J; Akasaki, I; Johnson, NM; Sopori, BL

Title: Magnetic circular dichroism of low-temperature-grown Al_xGa_{1-x}As

Source: DEFECT AND IMPURITY ENGINEERED SEMICONDUCTORS AND DEVICES

Book Series Title: MATERIALS RESEARCH SOCIETY SYMPOSIUM PROCEEDINGS

Volume: 378

Pages: 207-212

Published: 1995

Conference Title: Symposium on Defect and Impurity Engineered Semiconductors and Devices, at the 1995 MRS Spring Meeting

Conference Date: APR 17-21, 1995

Conference Location: SAN FRANCISCO, CA

Sponsor(s): MRS

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ISSN: 0272-9172

ISBN: 1-55899-281-2

Record 49 of 56

Author(s): STALLINGA, P; GREGORKIEWICZ, T; AMMERLAAN, CAJ

Title: ELECTRON-PARAMAGNETIC-RESONANCE OF MOLECULAR-HYDROGEN IN SILICON - REPLY

Source: PHYSICAL REVIEW LETTERS

Volume: 73

Issue: 10

Pages: 1457-1457

DOI: 10.1103/PhysRevLett.73.1457

Published: SEP 5 1994

Times Cited in Web of Science: 6

Total Times Cited: 6

ISSN: 0031-9007

Record 50 of 56

Author(s): SURMA, M; ZYTKIEWICZ, Z; FRONC, K; GODLEWSKI, M; STALLINGA, P; MONEMAR, B

Title: MAGNETIC-RESONANCE STUDIES OF TELLURIUM-DOPED ALXGA1-XAS

Source: PHYSICAL REVIEW B

Volume: 50

Issue: 4

Pages: 2645-2648

DOI: 10.1103/PhysRevB.50.2645

Published: JUL 15 1994

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ISSN: 0163-1829

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Record 51 of 56**Author(s):** STALLINGA, P; GREGORKIEWICZ, T; AMMERLAAN, CAJ; GORELKINSKII, YV**Title:** ELECTRON-PARAMAGNETIC-RESONANCE STUDY OF THE NL51 SPECTRUM IN HYDROGEN-IMPLANTED SILICON**Source:** SOLID STATE COMMUNICATIONS**Volume:** 90**Issue:** 6**Pages:** 401-404**DOI:** 10.1016/0038-1098(94)90808-7**Published:** MAY 1994**Times Cited in Web of Science:** 10**Total Times Cited:** 10**ISSN:** 0038-1098

Record 52 of 56**Author(s):** STALLINGA, P; GREGORKIEWICZ, T; AMMERLAAN, CAJ**Editor(s):** Glembocki, OJ; Pang, SW; Pollak, FH; Crean, GM; Larrabee, G**Title:** TRAPPING OF MOLECULAR-HYDROGEN IN POROUS SILICON AND AT SI/SIO2 INTERFACES AND A POSSIBLE REINTERPRETATION OF THE P(B) CENTER**Source:** DIAGNOSTIC TECHNIQUES FOR SEMICONDUCTOR MATERIALS PROCESSING**Book Series Title:** MATERIALS RESEARCH SOCIETY SYMPOSIUM PROCEEDINGS**Volume:** 324**Pages:** 385-390**Published:** 1994**Conference Title:** Symposium on Diagnostic Techniques for Semiconductor Materials Processing, held as part of the 1993 Fall Meeting of the Materials-Research-Society**Conference Date:** NOV 29-DEC 02, 1993**Conference Location:** BOSTON, MA**Sponsor(s):** MAT RES SOC; ASTEX, APPL SCI & TECHNOL; DIGITAL INSTRUMENTS, INC; MKS INSTRUMENTS, INC; USN, NAVAL RES LAB; USN, OFF NAVAL RES**Times Cited in Web of Science:** 1**Total Times Cited:** 1**ISSN:** 0272-9172**ISBN:** 1-55899-223-5

Record 53 of 56**Author(s):** STALLINGA, P; GREGORKIEWICZ, T; AMMERLAAN, CAJ; GORELKINSKII, YV**Editor(s):** Heinrich, H; Jantsch, W**Title:** EPR IDENTIFICATION OF HYDROGEN MOLECULES IN BULK SILICON**Source:** PROCEEDINGS OF THE 17TH INTERNATIONAL CONFERENCE ON DEFECTS IN SEMICONDUCTORS, PTS 1-3: ICDS-17**Book Series Title:** MATERIALS SCIENCE FORUM**Volume:** 143-**Pages:** 853-860**Part:** Part 1-3

Published: 1994

Conference Title: 17th International Conference on Defects in Semiconductors

Conference Date: JUL 18-23, 1993

Conference Location: GMUNDEN, AUSTRIA

Sponsor(s): AUSTRIAN PHYS SOC; BUNDESMINIST WISSENSCH & FORSCH; CITY GMUNDEN; CITY LINZ; COHERENT GMBH; COMETT; GESELL MIKROELEKTR; GOV'T UPPER AUSTRIA; HANDELSKAMMER OBEROSTERREICH; IBM; INT SCI FDN, NEW YORK; OBEROSTERREICH KRAFTWERKE A G; OSTERREICH FORSCHUNGSGEMENINSCH; OSTERREICH NATIONALBANK; SIEMEN AG; USN, OFF NAVAL RES

Times Cited in Web of Science: 4

Total Times Cited: 4

ISSN: 0255-5476

ISBN: 0-87849-671-8

Record 54 of 56

Author(s): SURMA, M; ZYTKIEWICZ, ZR; FRONC, K; STALLINGA, P; GODLEWSKI, M

Title: PHOTO-ESR STUDY OF THE DX TO SHALLOW DONOR CONVERSION IN TE DOPED ALXGA1-XAS

Source: ACTA PHYSICA POLONICA A

Volume: 84

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Pages: 757-760

Published: OCT 1993

Conference Title: 22ND INTERNATIONAL SCHOOL ON PHYSICS OF SEMICONDUCTING COMPOUNDS

Conference Date: MAY 22-28, 1993

Conference Location: JASZOWIEC, POLAND

Sponsor(s): POLISH ACAD SCI, INST PHYS; WARSAW UNIV, FAC PHYS

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ISSN: 0587-4246

Record 55 of 56

Author(s): STALLINGA, P; GREGORKIEWICZ, T; AMMERLAAN, CAJ; GORELKINSKII, YV

Title: ELECTRON-PARAMAGNETIC-RESONANCE OF MOLECULAR-HYDROGEN IN SILICON

Source: PHYSICAL REVIEW LETTERS

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ISSN: 0031-9007

Record 56 of 56

Author(s): STALLINGA, P; GREGORKIEWICZ, T; AMMERLAAN, CAJ

Title: ELECTRON-PARAMAGNETIC RESONANCE STUDY OF NEW CENTERS IN SIC

Source: MATERIALS SCIENCE AND ENGINEERING B-SOLID STATE MATERIALS FOR ADVANCED TECHNOLOGY

Volume: 11

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Pages: 35-38

DOI: 10.1016/0921-5107(92)90185-C

Published: JAN 15 1992

Conference Title: SYMP AT THE 1990 FALL MEETING OF THE EUROPEAN MATERIALS RESEARCH SOC :
PROPERTIES AND APPLICATIONS OF SIC, NATURAL AND SYNTHETIC DIAMOND AND RELATED MATERIALS

Conference Date: NOV 27-30, 1990

Conference Location: STRASBOURG, FRANCE

Sponsor(s): EUROPEAN MAT RES SOC; COUNCIL EUROPE; COMMISS EUROPEAN COMMUNITIES; USAF, OFF
SCI RES; BANQUE POPULAIRE; CTR RECH NUCL; CNRS; NEWPORT; PALAIS CONGRES STRASBOURG, SERV
DOCUMENTAT TOURIST; EUROPEAN PARLIMENT

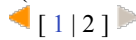
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